



Article Testing of Grouped Product for the Weibull Distribution Using Neutrosophic Statistics

Muhammad Aslam * D and Osama H. Arif

Department of Statistics, Faculty of Science, King Abdulaziz University, Jeddah 21589, Saudi Arabia; oharif@hotmail.com

* Correspondence: magmuhammad@kau.edu.sa or aslam_ravian@hotmail.com; Tel.: +966-593-329-841

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Abstract: Parts manufacturers use sudden death testing to reduce the testing time of experiments. The sudden death testing plan in the literature can only be applied when all observations of failure time/parameters are crisp. In practice however, it is noted that not all measurements of continuous variables are precise. Therefore, the existing sudden death test plan can be applied if failure data/or parameters are imprecise, incomplete, and fuzzy. The classical statistics have the special case of neutrosophic statistics when there are no fuzzy observations/parameters. The neutrosophic fuzzy statistics can be applied for the testing of manufacturing parts when observations are imprecise, incomplete and fuzzy. In this paper, we will design an original neutrosophic fuzzy sudden death testing plan for the inspection/testing of the electronic product or parts manufacturing. We will assume that the lifetime of the product follows the neutrosophic fuzzy Weibull distribution. The neutrosophic fuzzy operating function will be given and used to determine the neutrosophic fuzzy plan parameters through a neutrosophic fuzzy optimization problem. The results of the proposed neutrosophic fuzzy death testing plan will be implemented with the aid of an example.

Keywords: neutrosophic fuzzy statistics; fuzzy approach; neutrosophic fuzzy plan parameters; fuzzy optimization problem; risks

1. Introduction

In life testing experiments, a random sample of items is usually selected, and a single item is installed on a single tester for the lot sentencing. This type of testing is costly as the number of testers is equal to the number of items that are selected for the testing purpose. Alternatively, the group sampling scheme is applied for the testing of more than one item on the single tester. Sudden death testing is implemented in groups to reduce the testing/inspection cost of the product. In sudden death testing, a random sample of size *n* is equally distributed to *g* groups having *r* items in each of the *g* groups. Reference [1] proposed the sudden test for the Weibull distribution. According to Reference [1] "The specimens in each group are tested identically & simultaneously on different testers. The 1st group of specimens is run until the 1st failure occurs. At this point, the surviving specimens are suspended & removed from testing. An equal set of new specimens numbering is next tested until the 1st failure. This process is repeated until one failure is generated from each of the groups". The sampling plan for sudden death testing has been considered by several authors in the literature, see for example References [1–3].

In the modern era, products are manufactured using advanced technology, which result in high quality and reliability. For the testing/inspection of a highly reliable product, it may not be possible to wait for the failures of the product for the lot sentencing. The two types of censoring widely applied to reduce the testing cost for a highly reliable product, are known as type-I censoring and type-II censoring. The testing is said to be type-I censoring if the time of experiment is fixed, and type-II if

the number of failures is specified for the testing/inspection of the product. The acceptance sampling plans for type-I and type-II censoring when the lifetime follows the Weibull distribution is designed by a number of researchers, including, for example, References [4–10].

The fuzzy approach is widely used when there is some uncertainty in the proportion of defectives. In practice, the experimenter may be indeterminate about the percentage of defectives. In this case, the traditional sampling plans can be applied for the inspection of the lot. Hence, a number of people have designed efficient sampling plans using the fuzzy approach, including, for example, References [11–26].

Parts manufacturers use sudden death testing to reduce the testing time of the experiment. The sudden death testing plan in the literature can only be applied when all observations of failure time/parameters are crisp. According to Reference [27], "all observations and measurements of continuous variables are not precise numbers but more or less non-precise. This imprecision is different from variability and errors. Therefore, lifetime data are also not precise numbers but more or less fuzzy. The best up-to-date mathematical model for this imprecision is so-called non-precise numbers". Therefore, the existing sudden death test plan can be applied if failure data or parameters are imprecise, incomplete, and fuzzy. The classical statistics have the special case of the neutrosophic statistics when there are no fuzzy observations/parameters. Thus, the neutrosophic fuzzy statistics can be applied for the testing of manufacturing parts when observations are imprecise, incomplete, and fuzzy. Recently, the authors of Reference [28] introduced the neutrosophic statistics in the area of acceptance sampling plan.

By exploring the literature, and to the best of the author's knowledge, there is no work on the design of neutrosophic fuzzy sudden death testing plan using the Weibull distribution. In this paper, we will design an original neutrosophic fuzzy sudden death testing plan for the inspection/testing of the electronic product or parts manufacturing. We will assume that the lifetime of the product follows the neutrosophic fuzzy Weibull distribution. The neutrosophic fuzzy operating function will be given and used to determine the neutrosophic fuzzy plan parameters through a neutrosophic fuzzy optimization problem. The results of the proposed neutrosophic fuzzy death testing plan will be implemented with the aid of an example.

2. Design of Proposed Plan

Suppose that $T_{Ni} \in \{T_L, T_U\} = i = 1, 2, 3, ..., n_N$ being a random sample from the neutrosophic fuzzy Weibull distribution with neutrosophic fuzzy shape parameter m_N and neutrosophic fuzzy scale parameter λ_N . The neutrosophic fuzzy Weibull distribution is defined by:

$$F_N(t_N; m_N, \lambda_N) = 1 - exp\left(-(t_N/\lambda_N)^{m_N}\right), t_N \ge 0$$
⁽¹⁾

Some more details on fuzzy based Weibull distribution can be seen in References [29,30].

It is assumed that items are tested identically and simultaneously in each group. We propose following a neutrosophic fuzzy sudden death testing plan. The quality characteristic beyond the lower specification limit *L* is defined as defective. Thus, the probability of defectiveness is given by:

$$p_N = p_{r_N} \{ T_N < L \} = F_N(L)$$
(2)

For the given p_N , the corresponding $\lambda_N L$ from Equation (2) is given by:

$$w_N = -ln(1 - p_N) = (\lambda_N L)^{m_N}$$
(3)

Step 1. Select a random sample $n_N \in \{n_L, n_U\}$ and distribute *r* items into $g_N \in \{g_L, g_U\}$ groups.

Step 2. Record first failure from *i*th group $(i = 1, 2, ..., g_N)$ and calculate neutrosophic fuzzy statistic $v_N = \sum_{i=1}^{g_N} Y_{iN}^m; g_N \in \{g_L, g_U\}, v_N \in \{v_L, v_U\}.$

Step 3. Accept lot of the product if $v_N \ge k_N L^m$, $k_N \epsilon \{k_{aL}, k_{aU}\}$ is a neutrosophic fuzzy acceptance number.

The proposed plan has two neutrosophic fuzzy parameters $g_N \in \{g_L, g_U\}$ and $k_N \in \{k_{aL}, k_{aU}\}$. The proposed sampling plan is the extension of the plan proposed in Reference [1]. The proposed sampling plan reduces to the plan in Reference [1] when $g_L = g_U = g$ and $k_{aL} = k_{aU} = k$. The operational process of the proposed plan is also shown in Figure 1.

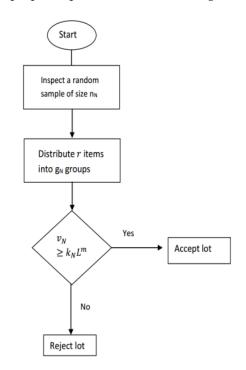


Figure 1. Operational procedure of proposed plan.

By following Reference [1] that Y_{iN}^m in $v_N = \sum_{i=1}^{g_N} Y_{iN}^m$ follows the i.i.d. neutrosophic exponential distribution with neutrosophic parameter $\lambda_N^{m_N} r_N$, so v_N follows the neutrosophic fuzzy gamma distribution with neutrosophic parameters $(g_N, \lambda_N^{m_N} r_N)$; $g_N \in \{g_L, g_U\}$. The neutrosophic fuzzy operating function (NFOC) will be derived as follows:

$$L(p_N) = 1 - G_{2g_N}(2r_N k_N w_N); \ k_N \epsilon\{k_{aL}, k_{aU}\}$$
(4)

where G_{δ_N} is the neutrosophic fuzzy cumulative distribution function of the neutrosophic fuzzy gamma with a neutrosophic degree of freedom δ_N .

Neutrosophic Fuzzy Non-Linear Optimization

Let α and β respectively be the producer's risk and consumer's risk. The plan parameters $g_N \epsilon \{g_L, g_U\}$ and $k_N \epsilon \{k_{aL}, k_{aU}\}$ will be determined $L(C_{AQL}) \geq 1 - \alpha$ at acceptable quality level (AQL = p_1) and $L(C_{LQL}) \leq \beta$ at limiting quality level (LQL = p_2). Therefore, the neutrosophic fuzzy plan parameters of the proposed plan will be determined by following the neutrosophic fuzzy non-linear optimization problem:

minimize
$$n_N \epsilon \{n_L, n_U\}$$
 (5)

$$L(C_{AQL}) = (1 - G_{2gN}(2r_Nk_Nw_{N0})) \ge 1 - \alpha, \ k_N \epsilon\{k_L, k_U\}; \ g_N \epsilon\{g_L, g_U\}$$

$$\tag{6}$$

$$L(C_{LQL}) = (1 - G_{2gN}(2r_Nk_Nw_{N1})) \le \beta, k_N \in \{k_L, k_U\}; g_N \in \{g_L, g_U\}$$

$$\tag{7}$$

The plan parameters $g_N \in \{g_L, g_U\}$ and $k_N \in \{k_{aL}, k_{aU}\}$ will be determined through Equations (5)–(7) using the grid search method. The following algorithm is used to determine the plan parameters.

Step 1. Specify the value of *r*.

Step 2. Determine the values of g_N and k_N using the search grid method through Equations (5)–(7).

Step 3. Choose the parameters for the plan where indeterminacy interval in g_N is minimum.

The combinations that have smaller values of $n_N \in \{n_L, n_U\}$ are selected and reported in Tables 1 and 2. Table 1 reports for $g_N \in \{g_L, g_U\}$ and $k_N \in \{k_{aL}, k_{aU}\}$ when r = 5 and Table 2 reports for $g_N \in \{g_L, g_U\}$ and $k_N \in \{k_{aL}, k_{aU}\}$ when r = 10. From Tables 1 and 2, we noted the following trend in $g_N \in \{g_L, g_U\}$ and $k_N \in \{k_{aL}, k_{aU}\}$.

- 1. For the fixed values of neutrosophic parameters, $g_N \epsilon \{g_L, g_U\}$ and $k_N \epsilon \{k_{aL}, k_{aU}\}$ decrease as r increases from 5 to 10.
- 2. For the fixed values of neutrosophic parameters, $g_N \in \{g_L, g_U\}$ and $k_N \in \{k_{aL}, k_{aU}\}$ decrease as LQL increases.

p_1	p_2		g_N	k_N	$L(C_{AQL})$	$L(C_{LQL})$
	0.000	Min	19	2473.2	0.952163	0.099984
	0.002	Max	21	2717.5	0.962712	0.095018
-	0.003	Min	8	783.6	0.953490	0.099964
	0.003	Max	10	953.3	0.975800	0.095052
	0.004	Min	6	462.9	0.969175	0.099899
	0.004	Max	8	592.6	0.988845	0.095073
0.001	0.006	Min	4	222.1	0.973434	0.099858
	0.006	Max	6	311.3	0.994680	0.095147
-	0.000	Min	3	132.6	0.970167	0.099792
	0.008	Max	5	201.2	0.996239	0.095123
-	0.010	Min	3	106.0	0.983213	0.099699
	0.010	Max	5	160.8	0.998555	0.095117
-	0.015	Min	2	51.5	0.971999	0.099838
	0.015	Max	4	89.4	0.998831	0.095418
-	0.020	Min	2	38.6	0.983592	0.099255
	0.020	Max	4	66.9	0.999599	0.095298
	0.00 -	Min	19	987.8	0.952444	0.099978
	0.005	Max	21	1085.3	0.962975	0.095069
-	0.010	Min	6	184.6	0.969462	0.099904
	0.010	Max	8	236.3	0.988989	0.095133
-	0.015	Min	4	88.5	0.973691	0.099564
0.0005		Max	6	123.9	0.994785	0.095364
0.0025	0.020	Min	3	52.7	0.983439	0.099924
-		Max	5	80.0	0.996321	0.095083
	0.005	Min	3	42.1	0.983490	0.099512
	0.025	Max	5	63.8	0.998600	0.095342
	0.030	Min	2	25.6	0.958424	0.099282
		Max	4	44.4	0.997442	0.095051
-	0.050	Min	2	15.2	0.984044	0.099320
	0.050	Max	4	26.3	0.999624	0.096062

Table 1. The neutrosophic plan optimal parameters when r = 5.

Table	1.	Cont.
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p_1	p_2		g_N	k_N	$L(C_{AQL})$	$L(C_{LQL})$
	0.010	Min	19	492.7	0.952885	0.099908
	0.010	Max	21	541.3	0.963371	0.095048
		Min	8	155.8	0.954335	0.099875
	0.015	Max	10	189.5	0.976377	0.095086
		Min	6	91.9	0.969849	0.099547
	0.020	Max	8	117.5	0.989243	0.095381
0.005		Min	4	43.9	0.974240	0.099688
	0.030	Max	6	61.5	0.994931	0.095194
		Min	3	26.1	0.971200	0.099658
	0.040	Max	5	39.5	0.996491	0.099038
	0.050	Min Max	3 5	20.8 31.5	0.983945 0.998668	0.099161 0.095215
	0.100	Min	2	7.4	0.984787	0.099317
		Max	4	12.8	0.999658	0.096182
	0.020	Min	19	245.1	0.953835	0.099928
		Max	21	269.2	0.964273	0.095309
	0.030	Min	8	77.3	0.955450	0.099925
	5.000	Max	10	94.0	0.977123	0.095270
	0.040	Min	5	39.2	0.950025	0.099569
0.01	0.040	Max	7	52.0	0.982409	0.095945
0.01	0.050	Min	4	26.1	0.955741	0.099193
	0.030	Max	6	36.5	0.988705	0.095461
	0.100	Min	3	10.2	0.984642	0.096525
	0.100	Max	5	15.3	0.998813	0.096244
	0.150	Min	2	4.8	0.975190	0.099150
	0.150	Max	4	8.3	0.999095	0.096094
	0.000	Min	2	3.5	0.986232	0.098790
	0.200	Max	4	6.0	0.999729	0.099160
	0.060	Min	19	80.1	0.957244	0.099165
		Max	21	87.9	0.967418	0.095266
	0.000	Min	8	25.0	0.959516	0.099143
	0.090	Max	10	30.3	0.980098	0.096447
0.03	0.120	Min	5	12.6	0.954365	0.096610
		Max	7	16.6	0.985015	0.096118
		Min	4	8.3	0.960407	0.096094
	0.150	Max	6	11.5	0.990833	0.096298
		Min	2	2.2	0.954964	0.097352
	0.300	Max	5	4.5	0.999285	0.097332
		Min	18	44.9	0.953778	0.098375
	0.100	Min Max	18 20	44.9 49.4	0.965643	0.098375
	0.150	Min Max	8 10	14.5 17.6	0.963878 0.982585	0.099439 0.095869
0.05						
0.05	0.200	Min Max	5 7	7.2 9.5	0.960131	0.097749
		Max			0.987505	0.096649
	0.250	Min	4	4.7	0.965761	0.095135
-		Max	6	6.5	0.992691	0.096047
	0.500	Min	2	1.2	0.961324	0.080608
	0.500	Max	6	2.7	0.999915	0.095643

p 1	p ₂		g_N	k_N	$L(C_{AQL})$	$L(C_{LQL})$
	0.000	Min	19	1236.6	0.952163	0.099984
	0.002	Max	21	1358.7	0.962724	0.095049
-	0.000	Min	8	391.8	0.953490	0.099964
	0.003	Max	10	476.6	0.975815	0.095115
-	0.004	Min	6	231.5	0.969147	0.099791
		Max	8	296.3	0.988845	0.095073
0.001		Min	4	111.1	0.973396	0.099670
0.001	0.006	Max	6	155.6	0.994688	0.095301
-		Min	3	66.3	0.970167	0.099792
	0.008	Max	5	100.6	0.996239	0.095123
-		Min	3	53.0	0.983213	0.099699
	0.010	Max	5	80.4	0.998555	0.095117
-		Min	2	25.8	0.971899	0.099239
	0.015	Max	4	44.7	0.998831	0.095418
-		Min	2	19.3	0.983592	0.099255
	0.020	Max	4	33.4	0.999602	0.095903
	0.005	Min	19	493.9	0.952444	0.099978
		Max	21	542.6	0.963004	0.095147
=	0.010	Min	6	92.3	0.969462	0.099904
	0.010	Max	8	118.1	0.989014	0.095364
-	0.015	Min	4	44.3	0.973597	0.099096
0.0025 -		Max	6	61.9	0.994805	0.095754
5.0025 -	0.020	Min	3	26.4	0.970450	0.099229
_	0.020	Max	5	40.0	0.996321	0.095083
	0.025	Min	3	21.1	0.983387	0.098644
-		Max	5	31.9	0.998600	0.095342
	0.030	Min	2	12.8	0.958424	0.099282
_	0.050	Max	4	22.2	0.997442	0.095051
	0.050	Min	2	7.6	0.984044	0.099320
		Max	4	13.1	0.999629	0.097616
	0.010	Min	19	246.4	0.952809	0.099739
-		Max	21	270.6	0.963430	0.095205
	0.015	Min	8	77.9	0.954335	0.099875
-		Max	10	94.7	0.976451	0.095405
	0.020	Min	6	46.0	0.969713	0.099008
0.005 -		Max	8	58.7	0.989294	0.095848
	0.030	Min	4	22.0	0.974054	0.098745
-		Max	6	30.7	0.994970	0.095980
	0.040	Min	3	13.1	0.970920	0.098260
	0.050	Max	5	19.7	0.996529	0.097257
		Min Max	3 E	10.4	0.983945	0.099161
		Max	5	15.7	0.998686	0.096635
	0.100	Min	2	3.7	0.984787	0.099317
		Max	4	6.4	0.999658	0.096182

Table 2. The neutrosophic plan optimal parameters when r = 10.

p 1	p ₂		g_N	k_N	$L(C_{AQL})$	$L(C_{LQL})$
	0.000	Min	19	122.6	0.953686	0.099588
	0.020	Max	21	134.6	0.964273	0.095309
	0.020	Min	8	38.7	0.955176	0.099196
	0.030	Max	10	47.0	0.977123	0.095270
	0.040	Min	5	19.6	0.950025	0.099569
0.01	0.040	Max	7	26.0	0.982409	0.095945
0.01	0.050	Min	4	13.1	0.955231	0.097616
	0.050	Max	6	18.2	0.988843	0.096790
	0.100	Min	3	5.1	0.984642	0.096525
	0.100	Max	5	7.6	0.998847	0.099210
	0.150	Min	2	2.4	0.975190	0.099150
	0.150	Max	3	3.3	0.995249	0.097215
	0.200	Min	2	1.8	0.985482	0.090371
	0.200	Max	4	3.0	0.999729	0.099160
	0.0(0	Min	19	40.1	0.956814	0.098132
	0.060	Max	21	43.9	0.967745	0.096233
	0.000	Min	8	12.5	0.959516	0.099143
	0.090	Max	10	15.1	0.980490	0.098475
0.03	0.120	Min	5	6.3	0.954365	0.096610
	0.120	Max	7	8.3	0.985015	0.096118
-	0.150	Min	4	4.2	0.958944	0.091311
		Max	7	6.5	0.995704	0.098411
	0.300	Min	2	1.1	0.954964	0.097352
		Max	3	1.5	0.988671	0.098094
	0.100	Min	18	22.5	0.952981	0.096593
		Max	20	24.7	0.965643	0.096049
	0.150	Min	8	7.3	0.962650	0.095621
0.05 -	0.150	Max	10	8.8	0.982585	0.095869
	0.200	Min	5	3.6	0.960131	0.097749
	0.200	Max	8	5.3	0.993116	0.097357
	0.250	Min	4	2.4	0.963476	0.086889
	0.250	Max	8	4.1	0.998501	0.098851
	0.500	Min	2	0.6	0.961324	0.080608
		Max	8	1.7	0.999996	0.099397

Table 2. Cont.

3. Application of Proposed Plan

The application of the proposed plan will be given on the ball bearing quality assurance, as the quality characteristic is measurable and as there is a chance that some observations may be fuzzy. Suppose that the ball bearing manufacturer is interested in applying the proposed sampling plan, but is not certain how to select suitable plan parameters for the testing of his product. Suppose he decides to install five items on the single tester. Let AQL = AQL = 0.001, LQL = 0.010, α = 0.05 and β = 0.10. From Table 1, we have $g_N \epsilon \{3, 5\}$ and $k_N \epsilon \{106.0, 160.8\}$. Hence, he can select *g* between 3 and 5. Suppose experimenter decides to select a random sample size *n* = 25 and *g* = 5.

Step 1. Select a random sample 25 and distribute five items into five groups.

Step 2. Perform sudden death testing and note down the first failure from each of the five groups (i = 1, 2, ..., 5). The number of first failures from the five groups are $Y_1 = [220, 230]$, $Y_2 = [300, 320]$, $Y_3 = 285$, $Y_4 = [155, 165]$ and $Y_5 = [365, 375]$. The lifetime of ball bearing follows

the neutrosophic Weibull distribution with parameter $m_N \epsilon \{2, 2\}$ and lower specification limit L = 200. The statistic v_N is calculated as:

$$v_N = \sum_{i=1}^{g_N} Y_{iN}^m; g_N \in \{3, 5\}, v_N \in \{106.0, 160.8\}$$

 $v_N = [220^2, 230^2] + [300^2, 320^2] + [285^2, 285^2] + [155^2, 165^2] + [365^2, 375^2] = [376875, 404375]$. Now $k_N L^{m_N} \epsilon \{4240000, 6432000\}$. As $v_N < k_N L^{m_N}$, so reject the lot of ball bearing product.

4. Comparison Study

In this section, we will compare the efficiency of the proposed plan using the neutrosophic statistics and the sudden death sampling plan proposed in Reference [2] using the classical (crisp) statistics in terms of plan parameter g. For fair comparison, we will consider the same plan parameter values. By comparing Table 1 of the proposed plan with Table 1 of Reference [2] when r = 5, it can be seen that the proposed plan provides smaller values of g as compared to the plan in Reference [2]. For easy reference, we present the comparison in g_N between the proposed plan and Reference [2] in Table 3. For example, when AQL = 0.001 and LQL = 0.002 in Table 3, the proposed plan has a minimum value of g = 17 and a maximum value of g = 21, while the plan in [2] provides a crisp value of g = 231. Therefore, the proposed plan needs a sample size of $n = r^*g$ between 85 and 105. By comparison, the existing plan needs a sample size of 1155 for the testing of the same lot of the product. From Table 3, we note that the proposed plan has a smaller g_N for all combinations of AQL and LQL. Therefore, the proposed plan has a smaller sample size for the inspection of the same product. Hence, less inspection cost is needed when the proposed sampling plan is implemented.

p_1	p_2	Proposed Plan	Existing Plan	
, -	, –	g_N	g	
	0.002	[19, 21]	231	
	0.003	[8, 10]	154	
0.001	0.004	[6, 8]	115	
	0.006	[4, 6]	77	
	0.008	[3, 5]	58	
	0.100	[18, 20]	34	
0.05	0.150	[8, 10]	16	
	0.200	[5, 7]	8	

Table 3. The comparison of proposed plan with the plan in Reference [2].

5. Concluding Remarks

In this paper, we have designed a neutrosophic fuzzy sudden death testing plan for the inspection/testing of the electronic product or parts manufacturing. The NFOC and neutrosophic fuzzy non-linear optimization problem are used to evaluate the proposed sampling plan. The proposed plan can be applied for the testing of parts when some observations or parameters are fuzzy. The proposed plan is the extension of a sudden death plan based on classical statistics. However, the proposed plan is more flexible than the plan based on classical statistics. Some tables are given and discussed with the help of a ball bearing example. The proposed plan can be applied for testing products in the automobile, aerospace and electronics industries. The proposed plan has the limitation that it can only be applied when the failure time follows the neutrosophic fuzzy Weibull distribution. The proposed plan for some other distribution can be considered as future research. The proposed sampling plan using big data can also be considered as future research.

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